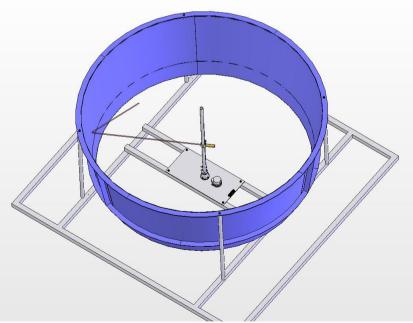
MIRROR REFLECTIVITY MAPPING

- We intend to perform a z-φ map using a spectrophotometer (Minolta CM-2600d)
- This tool was used by CGS for mirror acceptance: a coarse map already available.
- The CM-2600d provides spectral reflectivity components (specular & non-specular) at fixed observation angle
- A semiautomatic setup has been designed to provide (~mm) accurate positioning for the measurement.
- A rotating mast holds a laser pointer which flashes the taget position on the mirror.
- Once the measurement is done, the mast rotates to the next φ position.
- When the ϕ scan is completed the pointer is manually fixed to a different height along the mast for a new scan at different z

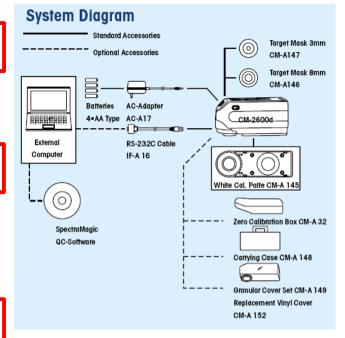


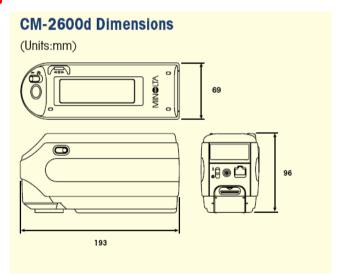


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	Specifications		
	llluminating/viewing system:	d/8 (diffused illumination, 8-degree viewing angle), equipped with	1
		simultaneous measurement of SCI	ı
		(specular component included)/SCE (specular component excluded).	L
		(Conforms to DIN 5033 Terl 7, JIS Z 8722 Condition C, ISO 7724/1,	Ī
	City of intograting enhance	CIE No.15, ASTM E1164.) B 52 mm	ł
	Size of integrating sphere: Detector:	Silicon photodiode array (dual 40 elements)	ł
	Spectral separation device:	Diffraction grating	ł
Н	Wavelength range:	360 nm to 740 nm	t
	Wavelength pitch:	10 nm	ł
	Half bandwidth:	Approx. 10 nm	ł
Ц	Reflectance range:	0 to 175%, Display resolution: 0.01%	۲
	Light source:	3 pulsed xenon lamps (2 xenon lamps for CM-2500 d)	ł
	Measurement time:	Approx. 1.5 seconds (approx. 2 seconds for fluorescent measurement)	1
	Minimum measurement interval:	3 seconds for SCI/SCE (4 seconds for fluorescent measurement)	1
		(Simultaneous evaluation of SCI/SCE is possible by a single measurement)	
	Measurement/Illumination area:	MAV: B 8mm/B 11 mm	1
		SAV: B 3 mm/B 6 mm (Selectable between MAV and SAV)	ı
		(Only MAV is available for OM 25004)	t
	Repeatability:	(Standard deviation): Spectral Reflectance: within 0.1% (360 to 380nm	ı
Ш		within 0.2%) Chromaticity Value : Delta E*ab within 0.04	L
		(When a white culibration plate is measured 80 times at 10-second intervals after white culibration)	Ι
	Inter Instrument agreement:	Delta E*ab within 0.2 (MAV/SCI) (Based on 12 BCRA Series	1
		Il color tiles compared to values measured with master body)	ı
	UV adjustment:	Instantaneous adjustment (no mechanical adjustment required)	1
		*With UV400nm cut filter (no UV adjustment function for CM-2500d)	1
	Measurement mode:	Single/averaging (auto mode: 3, 5, 8 flashes/manual mode)	1
	Interface:	RS-232C	4
	Observation:	2/10 degrees	4
	Observation light source:	A, C, D50, D65, F2, F6, F7, F8, F10, F11, F12	ı
	Outputs:	(simultaneous evaluation is possible using two light sources) Spectral value/graph, colorimetric value, color difference value/graph,	ł
	ourpuis.	PASS / FAIL result	ı
	Color space/colorimetric data:	L*a*b, L*C*h, CMC (1:1), (2:1), CIE94, Hunter Lab, DIN99	1
		Yxy, Munsell, XYZ, MI, WI (ASTM E313), WI/Tint CIE (Ganz/Griesser),	ı
		YI (ASTM E313/ASTM D1925), ISO Brightness (ISO 2470),	ı
		Density status A/T	1
	Data memory:	700 (SCI/SCE as a set)	-
	Tolerance judgment:	Tolerance for color difference (both box and elliptical tolerances can be set)	-
	Power sources:	AA-size battery (x4), AC adapter	4
П	Clas (Mullup)	20 - 20 - 100 - 100	Ť
	SIZE (WXHXD):	69 x 96 x 193 mm	1
Ц	Weight: Operating environment:	Approx. 670g (without batteries) 5 to 40 °C; less than 80% KH (no condensation); installation category: 2;	Ļ
	operating chandingent.	Pollution degree: 2	
	Storage environment:	0 to 45 °C; less than 80% RH (no condensation)	1
	Standard accessories:	White calibration plate, Target mask B 8 mm, Target mask B 3 mm	1
		(not supplied for CM-2500d), RS-232C cable, AC adapter, AA-size battery (x4))
	Optional accessories:	Hard case, Dust cover set, Dust cover, SpectraMagic QC software,	1
		Zero calibration box CM-A32	
			-

Specifications and drawings subject to change without prior notice.



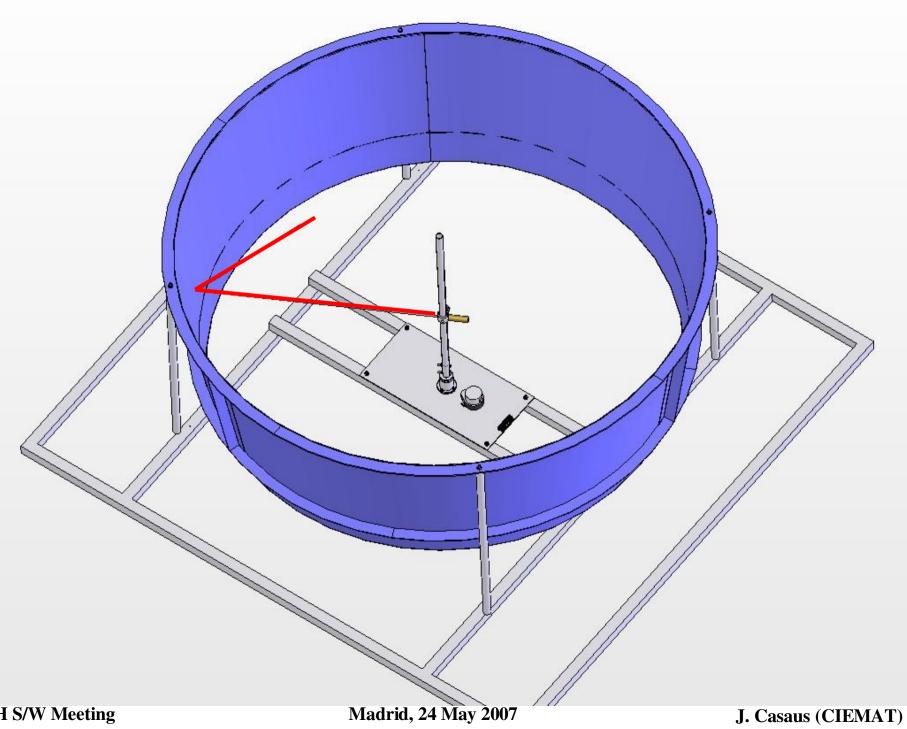


CM-2500d the lower cost option

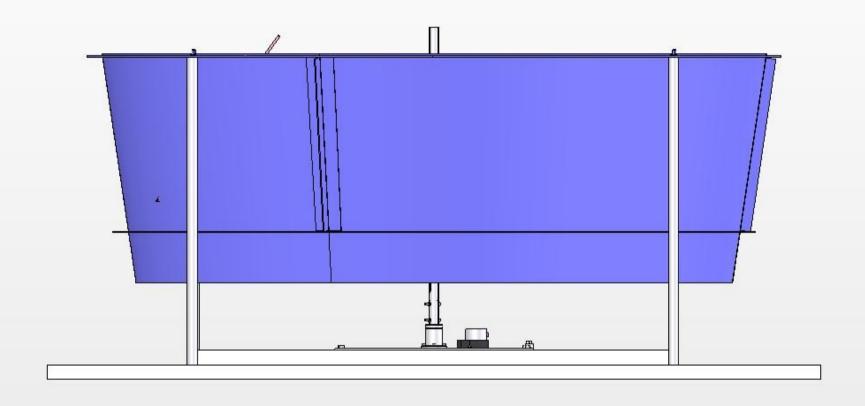
Same simplicity, same performance but with the following restrictions:

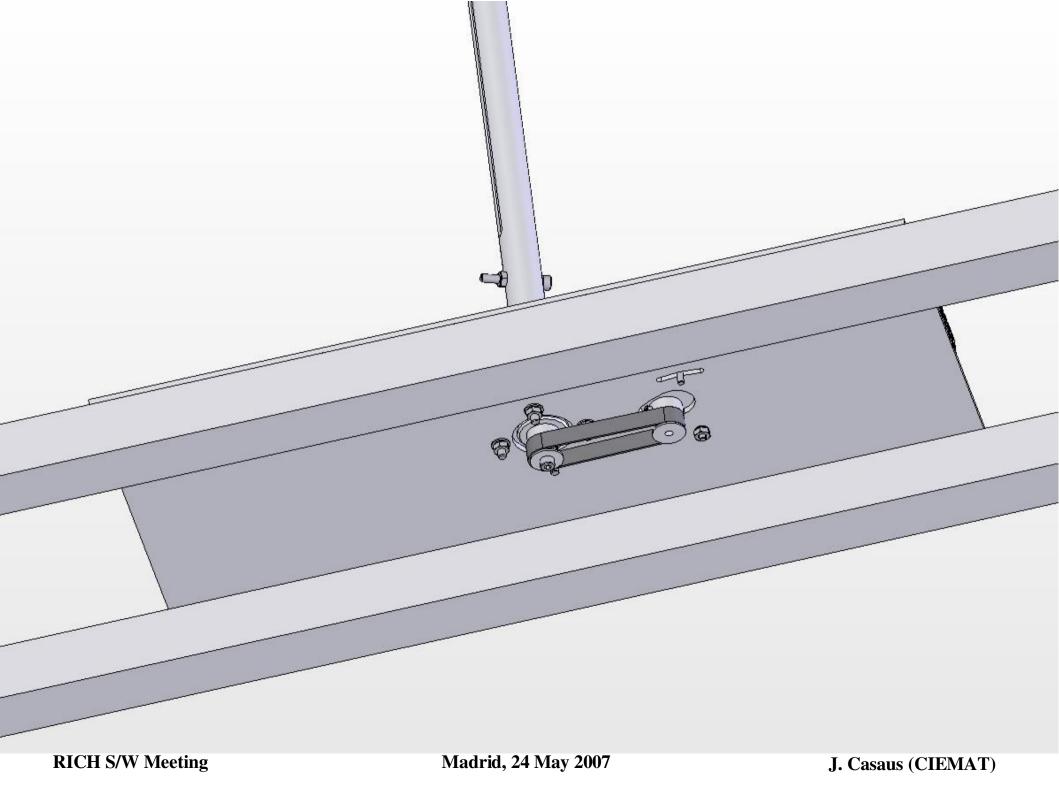
- No UV control
- Only B 8 mm apperture





RICH S/W Meeting





Possible Mapping:

• \$\phi\$-scan: 36 x 10 deg step (10.5 − 11.7 cm on the mirror)

• z-scan: 22 x 2 cm step

~800 measurements (~1 week)

Schedule:

- since the measurements will be carried out in the clean room, we must match the RICH assembly schedule.
- 2nd fortnight in June seems a sensible period to perform the measurements.
 - 1 week setup validation
 - 1 week for measurements

• S/W Implementation:

DB: Associated table (TBD)

SIM/REC S/W: mapping inclusion & interpolation procedure (TBD)